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August 12, 2011

DPF2011



Outline

- Radiation damage in VCSEL and PIN
- Results on PIN with protons/pions irradiation
- Results on VCSEL with protons/pions irradiation
- Summary

Radiation Damage in VCSEL/PIN

- optical links use VCSEL and PIN:
 - Vertical-Cavity Surface-Emitting Laser to convert electrical signal into optical signal
 - PIN diode to convert optical signal back into electrical signal
- main effect of radiation:
 - bulk damage, i.e. displacement of atoms
- high speed VCSEL/PIN are fabricated using GaAs instead of silicon
- VCSEL/PIN in collider experiments are exposed to mixture of particle species
 - use NIEL hypothesis to estimate fluence:
 - damage is proportional to non ionizing energy loss

Fluence at High Luminosity-LHC

- Expected fluence for 3,000 fb⁻¹ at radius of 37 cm
 - 2.8×10^{15} 1-MeV n_{eq}/cm^2
 - $5.4 \times 10^{14} p/cm^2$ for 24 GeV protons
- Study degradation with 24 GeV protons and 300 MeV/c pions
 - NIEL hypothesis: 300 MeV pion is 1.5 more damaging

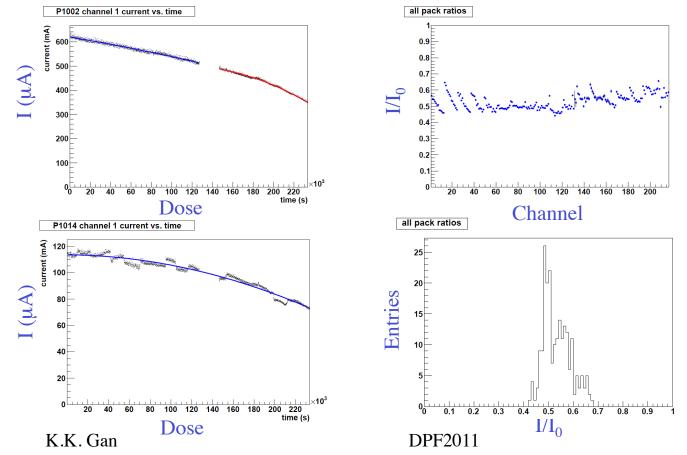
VCSEL/PIN Irradiation

- Study radiation hardness of VCSEL/PIN arrays since 2006:
 - vendors: AOC, Optowell, ULM, Hamamatsu
 - speed: up to 10 Gb/s
 - results: identified following devices for irradiation with 20 arrays
 - Optowell 3.125 Gb/s PIN arrays (2009): large leakage current
 - ULM 4.25 Gb/s PIN arrays (2010): see next slides
 - AOC 10 Gb/s VCSEL (2010): see next slides

Irradiation of PIN with Protons

20 ULM 12-channel PIN arrays (4.25 Gb/s) were irradiated to a dose of $1.0 \ge 10^{15} p/cm^2$ (24 GeV/c)

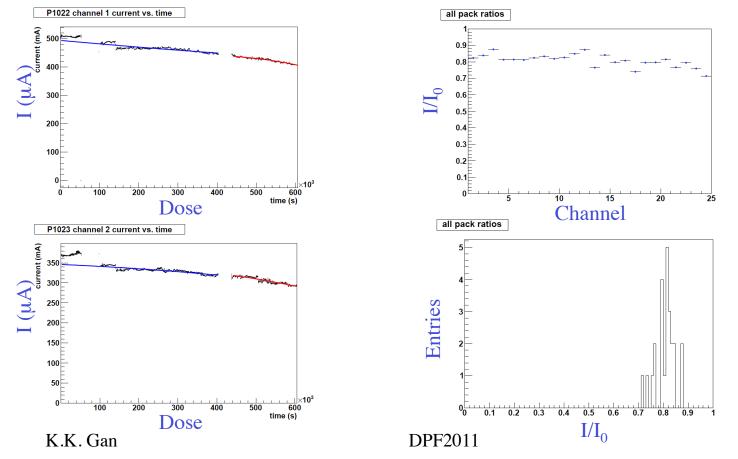
• decrease in PIN responsitivity is modest



Irradiation of PIN with Pions

2 ULM 12-channel PIN arrays (4.25 Gb/s) were irradiated to a dose of 4.3 x $10^{14} \pi/cm^2$ (300 MeV/c)

decrease in PIN responsitivity is small





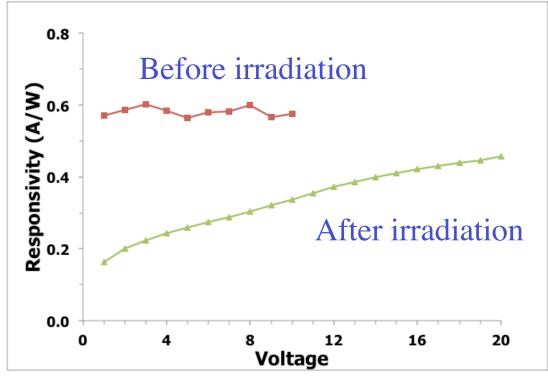
Test of NIEL Hypothesis

- NIEL hypothesis:
 - damage is proportional to the non ionizing energy loss
 - 300 MeV pion is 1.5 more damaging than 24 GeV protons
 - decrease in PIN responsivity with 4.3 x $10^{14} \pi/\text{cm}^2$: 81%
 - decrease in PIN responsivity with 6.6 x $10^{14} p/cm^2$: 78%
 - ➡ consistent with NIEL hypothesis

Resposivity vs Voltage

Before irradiation: reach responsivity plateau at relatively low voltage

- After irradiation: can partially recover responsivity with higher voltage
 - need to verify the high-speed operation



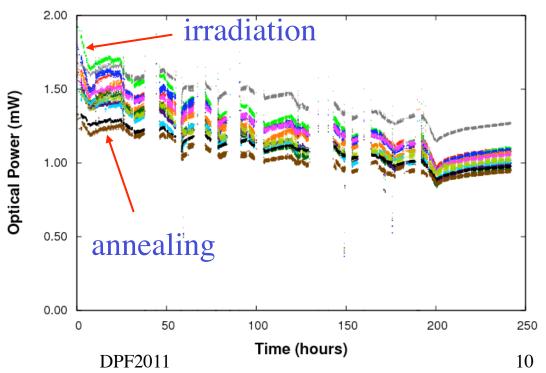
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Proton Irradiation of VCSEL

12 AOC arrays (10 Gb/s) irradiated to 8.0 x $10^{14} p/cm^2$ (24 GeV/c)

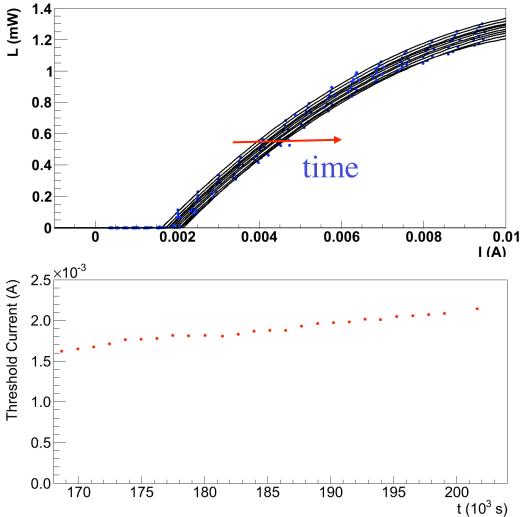
- alternate between irradiation and annealing (biased/no radiation)
- decrease in optical power is modest
- annealing in progress
 - ➡ will recover most lost optical power



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Radiation Effect on Threshold Current

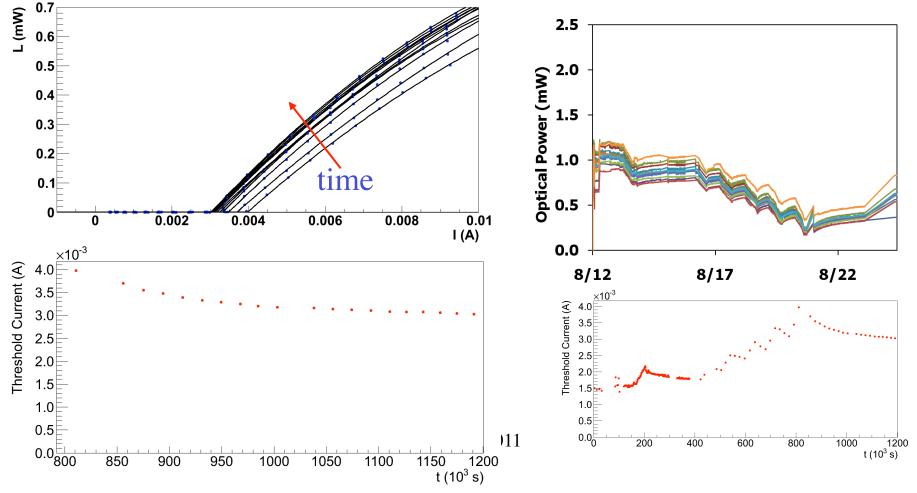
- Radiation damage increases current threshold for lasing
 - ➡ decrease optical power at same drive current



Annealing of Radiation Damage

Radiation damage can be annealed by drive current in VCSEL

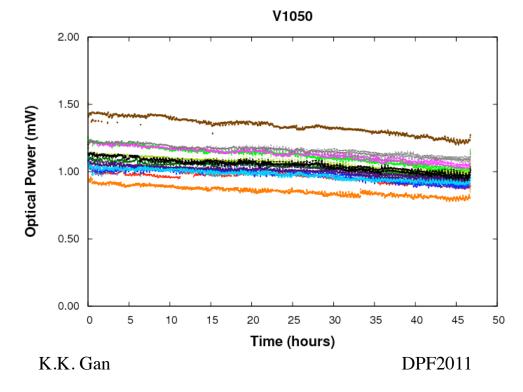
- decrease in threshold current
- ➡ increase in optical power at same drive current



Pion Irradiation of VCSEL

One AOC 10 Gb/s VCSEL array was irradiated:

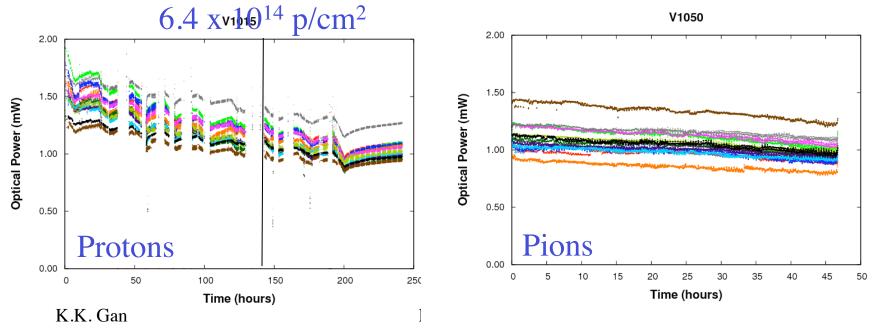
- dose: $4.1 \times 10^{14} \pi/cm^2 (300 \text{ MeV/c})$
- continuous irradiation with no dedicated annealing period due to limited time slot
- decrease in optical power is modest



Test of NIEL Hypothesis

• NIEL hypothesis:

- damage is proportional to the non ionizing energy loss
- 300 MeV pion is 1.5 more damaging than 24 GeV protons
- damage with 4.1 x 10¹⁴ π/cm^2 is equivalent to 6.4 x 10¹⁴ p/cm^2 ?
- need to repeat proton irradiation with no dedicated annealing
 - difficult to receive the exact required dose in 47 hours



Plan for VCSEL/PIN Array Irradiation

AOC 10 Gb/s VCSEL arrays:

- NIEL study: need to perform proton irradiation with no dedicated annealing
- need to repeat proton irradiation with higher statistics
 - half of arrays produced no light before irradiation last summer
 - AOC claimed due to material from sticky membrane

• ULM 10 Gb/s PIN arrays:

• will test two of these newly available arrays to start



Summary

- ULM PIN arrays: modest decrease in responsivity after irradiation
 damage from pion/proton consistent with NIEL hypothesis
- AOC VCSEL arrays: modest decrease in opto-power after irradiation
- more irradiation of 10 Gb/s PIN/VCSEL arrays this summer
 - attempting proton irradiation of VCSEL arrays with precise dosage and no dedicated annealing to test NIEL hypothesis